Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/722,155	SANA ET AL.	
Examiner	Art Unit	. <u> </u>
Young J. Kim	1637	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	9/11/2006	YJK